

Applicant: Ippei Shake et al.

Confirmation No.: 4422

Serial No.: 10/585,532

Att'y Docket No.: 14321.87

Filing Date: July 10, 2006

Art Unit: 2613

For: OPTICAL SIGNAL QUALITY MONITORING CIRCUIT AND OPTICAL SIGNAL
QUALITY MONITORING METHODSUPPLEMENTAL INFORMATION DISCLOSURE CITATIONS MADE BY APPLICANTU.S. Patent Documents

Examiner <u>Initial*</u>	Document <u>Number</u>	Issue <u>Date</u>	Name
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Foreign Patent Documents

Examiner <u>Initial*</u>	Document <u>Number</u>	Publication <u>Date</u>	Country or <u>Patent Office</u>	<u>Translation</u>
_____ 1	EP 1 363 423 A2	11/19/2003	Europe	N/A

Other Documents

(including author, title, pertinent pages, etc.)

Examiner
Initial*

_____ 2 Office Action from Chinese Patent Office dated March 6, 2009 for corresponding Chinese Application No. 2005-80002207.1 which relates to the same invention as the present application.

References Cited by Applicants

While the filing of Information Disclosure Statements is voluntary, the procedure is governed by the guidelines of Section 609 of the Manual of Patent Examining Procedure and 37 C.F.R. §§ 1.97 and 1.98. To be considered a proper Information Disclosure Statement, Form PTO-1449 shall be accompanied by a copy of each listed patent or publication or other item of information and a translation of the pertinent portions of foreign documents (if an existing translation is readily available to the applicant), an explanation of relevance of each reference not in the English language, and should be submitted in a timely manner as set out in MPEP Sec. 609.

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The reference designations "A1," "A2," etc. (referring to Applicant's reference 1, Applicant's reference 2, etc.) will be used by the Examiner in the same manner as Examiner's reference designations "A," "B," "C," etc. on Office Action Form PTO-1142.

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